

PATENT
81790.0189

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of:

MOMOHARA, Tomomi

Serial No: 09/686,200 (reissue of U.S. Patent
No. 5,818,249)

Filed: October 5, 2000

For: PROBE CARD HAVING GROUPS
OF PROBE NEEDLES IN A
PROBING TEST APPARATUS FOR
TESTING SEMICONDUCTOR
INTEGRATED CIRCUITS

Art Unit: 2829

Examiner: NGUYEN, Vinh P.

I hereby certify that this correspondence is being
facsimile transmitted to the United States Patent
and Trademark Office at (703) 872-9306, on:December 24, 2003
Date of DepositMichael Crapenhof, Reg. No. 37,115
Name December 24, 2003
Signature DatePETITION FOR EXTENSION OF TIMECommissioner for Patents
Alexandria, VA 22313-1450

Dear Sir:

In accordance with 37 C.F.R. 1.136, Applicant respectfully petitions the Commissioner for a five-month extension of time extending to December 25, 2003, the period for response to the Office communication dated June 25, 2003.

Please charge the fee of \$2010.00 for this extension to Deposit Account No. 50-1314. The responsive papers are attached.

Please charge any insufficiency or credit any overpayment to Deposit Account No. 50-1314. A copy of this petition is enclosed.

Respectfully submitted,

HOGAN & HARTSON L.L.P.

By: Michael L. Crapenhof
Registration No. 37,115
Attorney for Applicant03/19/2004 RMISE1 00000001 501314 09686200
Date: December 24, 2003
01 FC:1255 2010.00 DA500 South Grand Avenue, Suite 1900
Los Angeles, California 90071
Phone: 213-337-6700
Fax: 213-337-6701